

Resource Summary Report

Generated by [RRID](#) on Aug 5, 2026

JEOL: JIB-4000PLUS Focused Ion Beam

RRID:SCR_020178

Type: Tool

Proper Citation

JEOL: JIB-4000PLUS Focused Ion Beam (RRID:SCR_020178)

Resource Information

URL: <https://www.jeol.co.jp/en/products/detail/JIB-4000PLUS.html>

Proper Citation: JEOL: JIB-4000PLUS Focused Ion Beam (RRID:SCR_020178)

Description: Focused ion beam that is milling and imaging system featuring high performance ion optical column

Resource Type: instrument resource

Keywords: Jeol, JEOL, Focused Ion Beam, Instrument Equipment, USEDit,

Availability: Commercially available

Resource Name: JEOL: JIB-4000PLUS Focused Ion Beam

Resource ID: SCR_020178

Alternate IDs: Model_Number_JIB-4000PLUS

Record Creation Time: 20220129T080349+0000

Record Last Update: 20260801T190645+0000

Ratings and Alerts

No rating or validation information has been found for JEOL: JIB-4000PLUS Focused Ion Beam.

No alerts have been found for JEOL: JIB-4000PLUS Focused Ion Beam.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.